

Search Notes

Application/Control No.

10/774,795

Examiner

John Q. Nguyen

Applicant(s)/Patent under
Reexamination

YODER ET AL.

Art Unit

3654

SEARCHED

Class	Subclass	Date	Examiner
242	390 394 397.5 403 419.5 557	12/9/2005	JN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR